

Notice of References Cited	Application/Control No. 10/525,842		Applicant(s)/Patent Under Reexamination CHOI ET AL.	
	Examiner Lien T. Tran		Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,045,847	04-2000	Nakamura et al.	426/508
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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